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January 1995 Revised January 1999

# 74ABT16501

# 18-Bit Universal Bus Transceivers with 3-STATE Outputs

### **General Description**

The ABT16501 18-bit universal bus transceiver combines D-type latches and D-type flip-flops to allow data flow in transparent, latched, and clocked modes.

Data flow in each direction is controlled by output-enable (OEAB and  $\overline{\text{OEBA}}$ ), latch-enable (LEAB and LEBA), and clock (CLKAB and CLKBA) inputs. For A-to-B data flow, the device operates in the transparent mode when LEAB is HIGH. When LEAB is LOW, the A data is latched if CLKAB is held at a HIGH or LOW logic level. If LEAB is LOW, the A bus data is stored in the latch/flip-flop on the LOW-to-HIGH transition of CLKAB. Output-enable OEAB is active-high. When OEAB is HIGH, the outputs are active. When OEAB is LOW, the outputs are in the high-impedance state.

Data flow for B to A is similar to that of A to B but uses  $\overline{\text{OEBA}}$ , LEBA, and CLKBA. The output enables are com-

plementary (OEAB is active HIGH and  $\overline{\text{OEBA}}$  is active LOW).

To ensure the high-impedance state during power up or power down, OE inputs should be tied to GND through a pulldown resistor; the minimum value of the resistor is determined by the current-sourcing capability of the driver.

#### **Features**

- Combines D-Type latches and D-Type flip-flops for operation in transparent, latched, or clocked mode
- Flow-through architecture optimizes PCB layout
- Guaranteed latch-up protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Non-destructive hot insertion capability

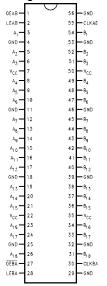
#### **Ordering Code:**

Order Number	Package Number	Package Description
74ABT16501CSSC	MS56A	56-Lead Shrink Small Outline Package (SSOP), JEDEC MO-118, 0.300" Wide
74ABT16501CMTD	MTD56	56-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide

Devices also available in Tape or Reel. Specify by appending the suffix letter "X" to the ordering code.

#### **Connection Diagram**

#### Pin Assignment for SSOP



#### Function Table (Note 1)

	Output			
OEAB	LEAB	CLKAB	Α	В
L	Х	Х	Х	Z
Н	Н	Χ	L	L
Н	Н	Χ	Н	Н
Н	L	$\uparrow$	L	L
Н	L	<b>↑</b>	Н	Н
Н	L	Н	X	B <sub>0</sub> (Note 2)
Н	L	L	X	B <sub>0</sub> (Note 3)

Note 1: A-to-B data flow is shown: B-to-A flow is similar but uses  $\overline{\text{OEBA}},$  LEBA, and CLKBA.

**Note 2:** Output level before the indicated steady-state input conditions were established.

Note 3: Output level before the indicated steady-state input conditions were established, provided that CLKAB was HIGH before LEAB went LOW.

Absolute Maximum Ratings(Note 4)

 $\begin{array}{lll} \mbox{Storage Temperature} & -65^{\circ}\mbox{C to } +150^{\circ}\mbox{C} \\ \mbox{Ambient Temperature under Bias} & -55^{\circ}\mbox{C to } +125^{\circ}\mbox{C} \\ \mbox{Junction Temperature under Bias} & -55^{\circ}\mbox{C to } +150^{\circ}\mbox{C} \\ \end{array}$ 

 $V_{\mbox{\footnotesize CC}}$  Pin Potential to

Voltage Applied to Any Output

in the Disabled or

Power-off State  $$-0.5 \mathrm{V}$ to 5.5 \mathrm{V}$$  in the HIGH State  $$-0.5 \mathrm{V}$ to $\mathrm{V}_{\mathrm{CC}}$$ 

Current Applied to Output

in LOW State (Max)  $\qquad \qquad \text{twice the rated I}_{\text{OL}} \, (\text{mA})$ 

DC Latchup Source Current -500 mA
Over Voltage Latchup (I/O) 10V

# Recommended Operating Conditions

Free Air Ambient Temperature -40°C to +85°C Supply Voltage +4.5V to +5.5V

Minimum Input Edge Rate ( $\Delta V/\Delta t$ )

Data Input 50 mV/ns
Enable Input 20 mV/ns

Note 4: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation

under these conditions is not implied.

Note 5: Either voltage limit or current limit is sufficient to protect inputs.

#### **DC Electrical Characteristics**

Symbol	Parameter	Min	Тур	Max	Units	v <sub>cc</sub>	Conditions
V <sub>IH</sub>	Input HIGH Voltage	2.0			V		Recognized HIGH Signal
V <sub>IL</sub>	Input LOW Voltage			0.8	V		Recognized LOW Signal
V <sub>CD</sub>	Input Clamp Diode Voltage			-1.2	V	Min	I <sub>IN</sub> = −18 mA
V <sub>OH</sub>	Output HIGH Voltage	2.5			V	Min	$I_{OH} = -3 \text{ mA}$
		2.0			V	Min	I <sub>OH</sub> = -32 mA
V <sub>OL</sub>	Output LOW Voltage			0.55	V	Min	I <sub>OL</sub> = 64 mA
I <sub>IH</sub>	Input HIGH Current			1	μΑ	Max	V <sub>IN</sub> = 2.7V (Note 6)
				1			$V_{IN} = V_{CC}$
I <sub>BVI</sub>	Input HIGH Current Breakdown Test			7	μΑ	Max	V <sub>IN</sub> = 7.0V
I <sub>IL</sub>	Input LOW Current			-1	μΑ	Max	V <sub>IN</sub> = 0.5V (Note 6)
				-1			$V_{IN} = 0.0V$
V <sub>ID</sub>	Input Leakage Test	4.75			V	0.0	$I_{ID} = 1.9 \mu\text{A}$
							All Other Pins Grounded
I <sub>IH</sub> +	Output Leakage Current			10	μА	0 – 5.5V	$V_{OUT} = 2.7V; \overline{OE}, OE = 2.0V$
lozh	Output Leakage Current					0 551/	
I <sub>IL</sub> +	Output Leakage Current			-10	μА	0 – 5.5V	$V_{OUT} = 0.5V; \overline{OE}, OE = 2.0V$
l <sub>OZL</sub>	0 + +0! +0: **0	400		075			
los	Output Short-Circuit Current	-100		-275	mA	Max	V <sub>OUT</sub> = 0V
I <sub>CEX</sub>	Output HIGH Leakage Current			50	μA	Max	V <sub>OUT</sub> = V <sub>CC</sub>
I <sub>ZZ</sub>	Bus Drainage Test			100	μA	0.0	V <sub>OUT</sub> = 5.5V; All Others GND
I <sub>CCH</sub>	Power Supply Current			1.0	mA	Max	All Outputs HIGH
I <sub>CCL</sub>	Power Supply Current			68	mA	Max	An or Bn Outputs LOW
I <sub>CCZ</sub>	Power Supply Current			1.0	mA	Max	$\overline{OE}_n = V_{CC}$
							All Others at V <sub>CC</sub> or GND
I <sub>CCT</sub>	Additional I <sub>CC</sub> /Input			2.5	mA	Max	$V_I = V_{CC} - 2.1V$
							All Others at V <sub>CC</sub> or GND
I <sub>CCD</sub>	Dynamic I <sub>CC</sub> No Load				mA/	Max	Outputs Open
	(Note 6)			0.23	MHz		Transparent Mode
							One Bit Toggling, 50% Duty Cycle

Note 6: Guaranteed, but not tested.

# **DC Electrical Characteristics**

Symbol	Parameter	Min	Тур	Max	Units	v <sub>cc</sub>	Conditions $\mathbf{C_L} = 50 \; \mathbf{pF}; \; \mathbf{R_L} = 500 \Omega$
V <sub>OLP</sub>	Quiet Output Maximum Dynamic V <sub>OL</sub>		0.7	1.2	V	5.0	T <sub>A</sub> = 25°C (Note 7)
V <sub>OLV</sub>	Quiet Output Minimum Dynamic V <sub>OL</sub>	-1.5	-1.0		V	5.0	T <sub>A</sub> = 25°C (Note 7)
V <sub>OHV</sub>	Minimum HIGH Level Dynamic Output Voltage	2.5	3.0		V	5.0	T <sub>A</sub> = 25°C (Note 8)
V <sub>IHD</sub>	Minimum HIGH Level Dynamic Input Voltage	2.2	1.8		V	5.0	T <sub>A</sub> = 25°C (Note 9)
V <sub>ILD</sub>	Maximum LOW Level Dynamic Input Voltage		1.2	0.8	V	5.0	T <sub>A</sub> = 25°C (Note 9)

Note 7: Max number of outputs defined as (n). n – 1 data inputs are driven 0V to 3V. One output at LOW. Guaranteed, but not tested.

## **AC Electrical Characteristics**

			$T_A = +25^{\circ}C$ $V_{CC} = +5V$ $C_L = 50 \text{ pF}$			C to +85°C	
Symbol	Parameter					$V_{CC} = 4.5V - 5.5V$ $C_L = 50 \text{ pF}$	
Gymbol	rarameter						
		Min	Тур	Max	Min	Max	
f <sub>max</sub>	Maximum Clock Frequency	150	200		150		MHz
t <sub>PLH</sub>	Propagation Delay	1.0	2.7	4.6	1.0	4.6	ns
t <sub>PHL</sub>	A or B to B or A	1.0	3.2	4.6	1.0	4.6	
t <sub>PLH</sub>	Propagation Delay	1.0	3.1	5.0	1.0	5.0	ns
t <sub>PHL</sub>	LEAB or LEBA to B or A	1.0	3.6	5.5	1.0	5.5	
t <sub>PLH</sub>	Propagation Delay	1.0	3.4	5.3	1.0	5.3	ns
t <sub>PHL</sub>	CLKAB or CLKBA to B or A	1.0	3.7	5.3	1.0	5.3	
t <sub>PZH</sub>	Propagation Delay	1.5	2.7	5.6	1.5	5.6	ns
t <sub>PZL</sub>	OEAB or OEBA to B or A	1.5	3.0	5.6	1.5	5.6	
t <sub>PHZ</sub>	Propagation Delay	1.5	3.7	6.0	1.5	6.0	ns
t <sub>PLZ</sub>	OEAB or OEBA to B or A	1.5	3.2	6.0	1.5	6.0	

# **AC Operating Requirements**

Symbol	Parameter	V <sub>CC</sub>	$T_A = +25^{\circ}C$ $V_{CC} = +5V$ $C_L = 50 \text{ pF}$		$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V} -5.5\text{V}$ $C_L = 50 \text{ pF}$	
		Min	Max	Min	Max	
t <sub>S</sub> (H)	Setup Time,	4.0		4.0		ns
t <sub>S</sub> (L)	A to CLKAB, B to CLKBA	4.0		4.0		
t <sub>H</sub> (H)	Hold Time,	0		0		ns
t <sub>H</sub> (L)	A to CLKAB, B to CLKBA	0		0		
t <sub>S</sub> (H)	Setup Time, A to LEAB	4.0		4.0		ns
t <sub>S</sub> (L)	or B to LEBA, CLK HIGH	4.0		4.0		
t <sub>H</sub> (H)	Hold Time, A to LEAB	1.5		1.5		ns
t <sub>H</sub> (L)	or B to LEBA, CLK HIGH	1.5		1.5		
t <sub>S</sub> (H)	Setup Time, A to LEAB	1.5		1.5		ns
$t_s(L)$	or B to LEBA, CLK LOW	1.5		1.5		
t <sub>H</sub> (H)	Hold Time, A to LEAB	1.5		1.5		
t <sub>H</sub> (L)	or B to LEBA, CLK LOW	1.5		1.5		ns
t <sub>W</sub> (H)	Pulse Width,	3.3		3.3		ns
$t_W(L)$	LEAB or LEBA, HIGH	3.3		3.3		
t <sub>W</sub> (H)	Pulse Width, CLKAB	3.3		3.3		ns
t <sub>W</sub> (L)	or CLKBA, HIGH or LOW	3.3		3.3		1

 $<sup>\</sup>textbf{Note 8:} \ \text{Max number of outputs defined as (n).} \ n-1 \ \text{data inputs are driven 0V to 3V.} \ \text{One output HIGH.} \ \text{Guaranteed, but not tested.}$ 

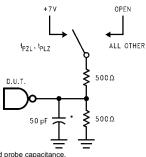
Note 9: Max number of data inputs (n) switching. n – 1 inputs switching 0V to 3V. Input-under-test switching: 3V to threshold (V<sub>ILD</sub>), 0V to threshold (V<sub>IHD</sub>). Guaranteed, but not tested.

## Capacitance

Symbol	Parameter	Тур	Units	Conditions T <sub>A</sub> = 25°C
C <sub>IN</sub>	Input Capacitance	5.0	pF	$V_{CC} = 0.0V$
C <sub>I/O</sub> (Note 10)	Output Capacitance	11.0	pF	$V_{CC} = 5.0V$

Note 10:  $C_{I/O}$  is measured at frequency f = 1 MHz per MIL-STD-883, Method 3012.

## **AC Loading**



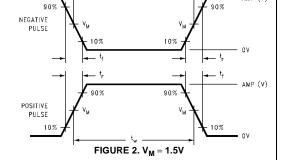


FIGURE 1. Standard AC Test Load

Input Pulse Requirements

Amplitude	Rep. Rate	t <sub>W</sub>	t <sub>r</sub>	t <sub>f</sub>
3.0V	1 MHz	500 ns	2.5 ns	2.5 ns

FIGURE 3. Test Input Signal Requirements

## **AC Waveforms**

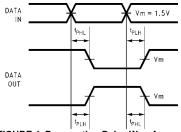


FIGURE 4. Propagation Delay Waveforms for Inverting and Non-Inverting Functions

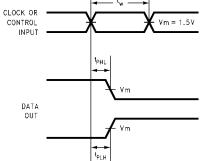


FIGURE 5. Propagation Delay, Pulse Width Waveforms

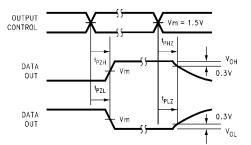
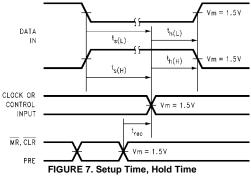
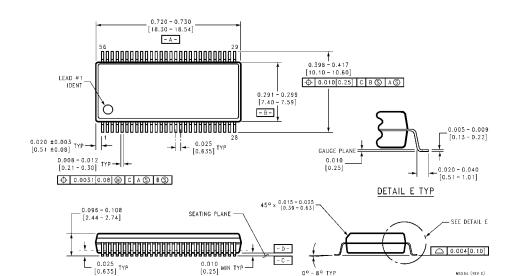


FIGURE 6. 3-STATE Output HIGH and LOW Enable and Disable Times

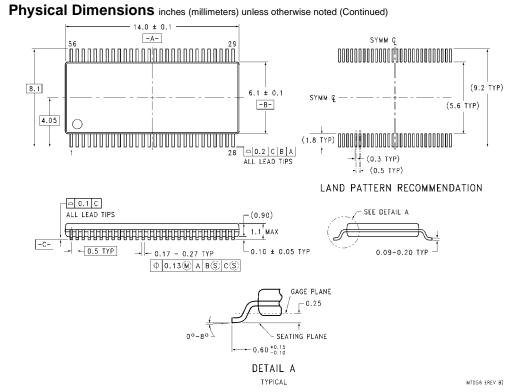


and Recovery Time Waveforms

# Physical Dimensions inches (millimeters) unless otherwise noted



56-Lead Shrink Small Outline Package (SSOP), JEDEC MO-118, 0.300" Wide Package Number MS56A



# 56-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide Package Number MTD56

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